

<b>Notice of References Cited</b>	Application/Control No. 10/007,620	Applicant(s)/Patent Under Reexamination BRUMMEL ET AL.	
	Examiner X. L. Bautista	Art Unit 2179	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0022973 A1	02-2002	Sun et al.	705/3
*	B	US-7,038,588 B2	05-2006	Boone et al.	340/573.1
*	C	US-2002/0010679 A1	01-2002	Felsher, David Paul	705/51
*	D	US-7,022,075 B2	04-2006	Grunwald et al.	600/446
*	E	US-2002/0116226 A1	08-2002	Auer et al.	705/3
*	F	US-5,115,501	05-1992	Kerr, Linda L.	707/9
*	G	US-5,495,567	02-1996	Iizawa et al.	715/762
*	H	US-5,535,321	07-1996	Massaro et al.	715/707
*	I	US-5,394,521	02-1995	Henderson et al.	715/804
*	J	US-5,874,958	02-1999	Ludolph, Frank	715/781
*	K	US-5,745,096	04-1998	Ludolph et al.	715/764
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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